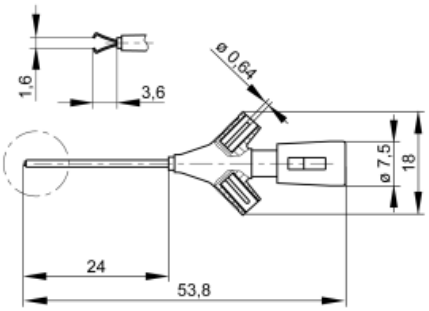
HIRSCHMANN
Test & Measurement

## Clamp-type test probe

# MICRO-KLEPS

CE

| **Product** | **MICRO-KLEPS** |
|---|---|
| description | Miniature clamp-type test probe with rotating grip jaws (SMD technology). The insulated shaft can be bent up to 35º. Suitable for very thin wires and densely packed contact points (1.27 mm IC spacing pitch). Connects with MKL... and MAL... |
| operating instruction | BA002 |
| article-no. /<br>*colour | 9739721xx<br>● 00 black<br>● 01 red |
| **drawing** | |
| |  |
| **technical data** | |
| connection | 2 x unsprung pin Ø 0.64 mm |
| rated voltage | 30 VAC / 60 VDC |
| measurement cat. acc. to IEC 61010 | O(2) |

0.64 mm system

| | |
|---|---|
| rated current<br>(consider derating curve) | 2 A |
| material plug | brass, gold plated |
| housing material | PBT |
| temperature range acc. To IEC61010[(1)] | -25 °C to +70 °C |
| inflammability class acc. to UL 94<br>(only valid for basic material of housing) | HB |
| clamp type | rotating grip jaws, tin plated |
| clamping range | 1,6 mm |

[(1)]contact the manufacturer for applications at deviating temperature ranges
[(2)]without rated measurement category, for other circuits that are not directly connected to mains
stand : November 13, 2025 5:59 PM